

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/763,645 GHOSH ET AL.	
		Examiner	Art Unit JOHN B. STREGE 2624	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Wang et al., Quantitative quality control in microarray image processing and data acquisition, Oxford University Press, 2001, Vol. 29, No. 15 e75
	V	
	W	
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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